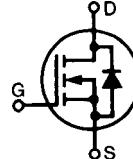


# HiPerFET™ Power MOSFETs

N-Channel Enhancement Mode  
High dv/dt, Low  $t_{rr}$ , HDMOS™ Family

**IXFH/IXFT 30N50**  
**IXFH/IXFT 32N50**

$V_{DSS}$	$I_{D25}$	$R_{DS(on)}$
500 V	30 A	0.16 Ω
500 V	32 A	0.15 Ω

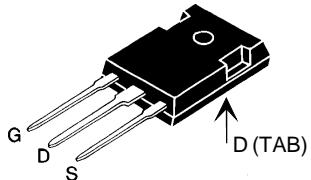


$t_{rr} \leq 250$  ns

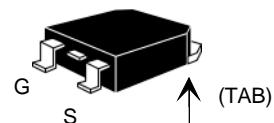
Symbol	Test Conditions	Maximum Ratings		
$V_{DSS}$	$T_J = 25^\circ\text{C}$ to $150^\circ\text{C}$	500	V	
$V_{DGR}$	$T_J = 25^\circ\text{C}$ to $150^\circ\text{C}$ ; $R_{GS} = 1\text{ M}\Omega$	500	V	
$V_{GS}$	Continuous	$\pm 20$	V	
$V_{GSM}$	Transient	$\pm 30$	V	
$I_{D25}$	$T_c = 25^\circ\text{C}$	30N50	30	A
		32N50	32	A
$I_{DM}$	$T_c = 25^\circ\text{C}$ pulse width limited by $T_{JM}$	30N50	120	A
		32N50	128	A
$I_{AR}$	$T_c = 25^\circ\text{C}$	30N50	30	A
		32N50	32	A
$E_{AS}$	$T_c = 25^\circ\text{C}$	1.5	J	
$E_{AR}$	$I_D = 25^\circ\text{C}$	45	mJ	
$dv/dt$	$I_S \leq I_{DM}$ , $di/dt \leq 100\text{ A}/\mu\text{s}$ , $V_{DD} \leq V_{DSS}$ , $T_J \leq 150^\circ\text{C}$ , $R_G = 2\text{ }\Omega$	5	V/ns	
$P_D$	$T_c = 25^\circ\text{C}$	360	W	
$T_J$		-55 ... +150	$^\circ\text{C}$	
$T_{JM}$		150	$^\circ\text{C}$	
$T_{stg}$		-55 ... +150	$^\circ\text{C}$	
$T_L$	1.6 mm (0.062 in.) from case for 10 s	300	$^\circ\text{C}$	
$M_d$	Mounting torque	1.13/10	Nm/lb.in.	
<b>Weight</b>		6	g	

Symbol	Test Conditions	Characteristic Values		
		( $T_J = 25^\circ\text{C}$ , unless otherwise specified)	min.	typ.
$V_{DSS}$	$V_{GS} = 0\text{ V}$ , $I_D = 1\text{ mA}$ $V_{DSS}$ temperature coefficient	500		V
			0.102	%/K
$V_{GS(th)}$	$V_{DS} = V_{GS}$ , $I_D = 4\text{ mA}$ $V_{GS(th)}$ temperature coefficient	2	4	V
			-0.206	%/K
$I_{GSS}$	$V_{GS} = \pm 20\text{ V}_{DC}$ , $V_{DS} = 0$	$\pm 100$		nA
$I_{DSS}$	$V_{DS} = 0.8 \cdot V_{DSS}$ $V_{GS} = 0\text{ V}$	$T_J = 25^\circ\text{C}$ $T_J = 125^\circ\text{C}$	200	$\mu\text{A}$ mA
$R_{DS(on)}$	$V_{GS} = 10\text{ V}$ , $I_D = 15\text{ A}$ Pulse test, $t \leq 300\text{ }\mu\text{s}$ , duty cycle $d \leq 2\%$	32N50 30N50	0.15 0.16	$\Omega$

TO-247 AD (IXFH)



TO-268 (D3) Case Style



G = Gate,  
S = Source,  
TAB = Drain

## Features

- International standard packages
- Low  $R_{DS(on)}$  HDMOS™ process
- Rugged polysilicon gate cell structure
- Unclamped Inductive Switching (UIS) rated
- Low package inductance
  - easy to drive and to protect
- Fast intrinsic Diode

## Applications

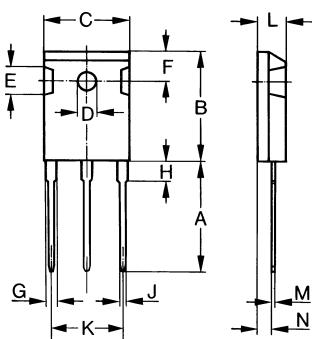
- DC-DC converters
- Battery chargers
- Switched-mode and resonant-mode power supplies
- DC choppers
- AC motor control
- Temperature and lighting controls

## Advantages

- Easy to mount with 1 screw (TO-247) (isolated mounting screw hole)
- Space savings
- High power density

**Symbol**    **Test Conditions**
**Characteristic Values**
 $(T_J = 25^\circ\text{C}$ , unless otherwise specified)

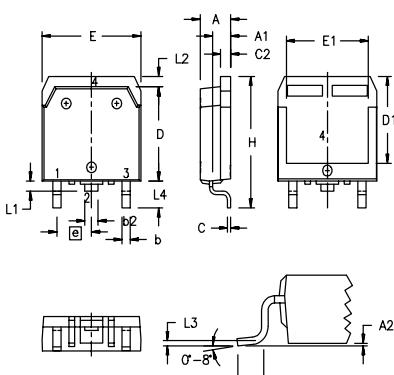
		min.	typ.	max.
$g_{fs}$	$V_{DS} = 10 \text{ V}; I_D = 0.5 I_{D25}$ , pulse test	18	28	S
$C_{iss}$ $C_{oss}$ $C_{rss}$	$V_{GS} = 0 \text{ V}, V_{DS} = 25 \text{ V}, f = 1 \text{ MHz}$	5200	5700	pF
		640	750	pF
		240	310	pF
$t_{d(on)}$ $t_r$ $t_{d(off)}$ $t_f$	$V_{GS} = 10 \text{ V}, V_{DS} = 0.5 V_{DSS}, I_D = 0.5 I_{D25}$ $R_G = 2 \Omega$ (External)	35	45	ns
		42	50	ns
		110	140	ns
		26	35	ns
$Q_{g(on)}$ $Q_{gs}$ $Q_{gd}$	$V_{GS} = 10 \text{ V}, V_{DS} = 0.5 V_{DSS}, I_D = 0.5 I_{D25}$	227	300	nC
		29	40	nC
		110	145	nC
$R_{thJC}$	(TO-247 Case Style)	0.25	0.35	K/W
$R_{thCK}$			0.25	K/W

**TO-247 AD (IXFH) Outline**


Dim.	Millimeter Min.	Max.	Inches Min.	Max.
A	19.81	20.32	0.780	0.800
B	20.80	21.46	0.819	0.845
C	15.75	16.26	0.610	0.640
D	3.55	3.65	0.140	0.144
E	4.32	5.49	0.170	0.216
F	5.4	6.2	0.212	0.244
G	1.65	2.13	0.065	0.084
H	-	4.5	-	0.177
J	1.0	1.4	0.040	0.055
K	10.8	11.0	0.426	0.433
L	4.7	5.3	0.185	0.209
M	0.4	0.8	0.016	0.031
N	1.5	2.49	0.087	0.102

**Source-Drain Diode**
**Characteristic Values**
 $(T_J = 25^\circ\text{C}$ , unless otherwise specified)

		min.	typ.	max.
$I_s$	$V_{GS} = 0 \text{ V}$	30N50		30 A
		32N50		32 A
$I_{SM}$	Repetitive; pulse width limited by $T_{JM}$	30N50		120 A
		32N50		128 A
$V_{SD}$	$I_F = I_s, V_{GS} = 0 \text{ V},$ Pulse test, $t \leq 300 \mu\text{s}$ , duty cycle $d \leq 2\%$			1.5 V
$t_{rr}$ $Q_{RM}$ $I_{RM}$	$I_F = I_s$ $-di/dt = 100 \text{ A}/\mu\text{s},$ $V_R = 100 \text{ V}$	$T_J = 25^\circ\text{C}$	250	ns
		$T_J = 125^\circ\text{C}$	400	ns
		$T_J = 25^\circ\text{C}$	0.85	$\mu\text{C}$
		$T_J = 25^\circ\text{C}$	8	A

**TO-268AA (D<sup>3</sup> PAK)**


Dim.	Millimeter Min.	Max.	Inches Min.	Max.
A	4.9	5.1	.193	.201
A <sub>1</sub>	2.7	2.9	.106	.114
A <sub>2</sub>	.02	.25	.001	.010
b	1.15	1.45	.045	.057
b <sub>2</sub>	1.9	2.1	.75	.83
C	.4	.65	.016	.026
D	13.80	14.00	.543	.551
E	15.85	16.05	.624	.632
E <sub>1</sub>	13.3	13.6	.524	.535
e	5.45 BSC		.215 BSC	
H	18.70	19.10	.736	.752
L	2.40	2.70	.094	.106
L1	1.20	1.40	.047	.055
L2	1.00	1.15	.039	.045
L3	0.25 BSC		.010 BSC	
L4	3.80	4.10	.150	.161

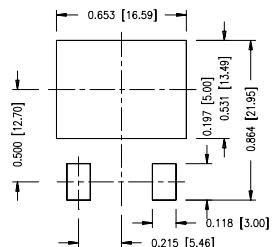
**Min. Recommended Footprint**


Figure 1. Output Characteristics at 25°C

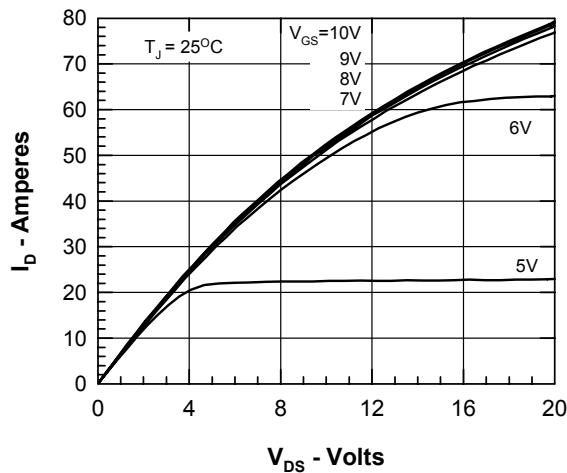


Figure 3.  $R_{DS(on)}$  normalized to 15A/25°C vs.  $I_D$

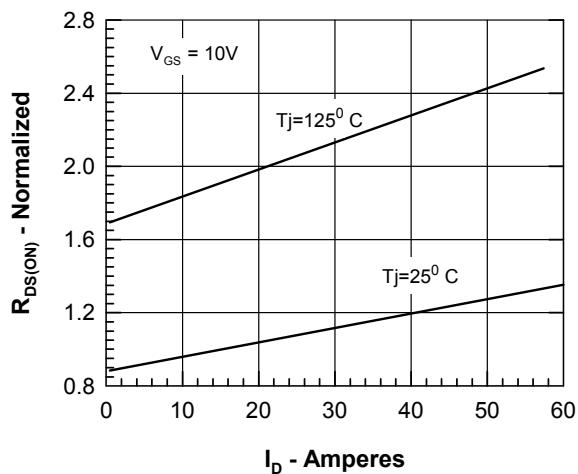


Figure 5. Drain Current vs. Case Temperature

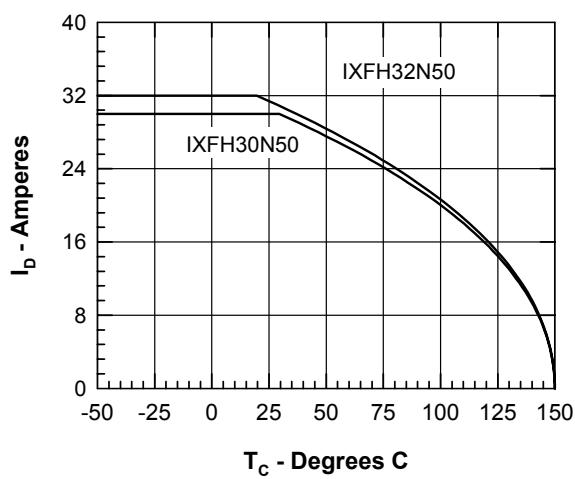


Figure 2. Output Characteristics at 125°C

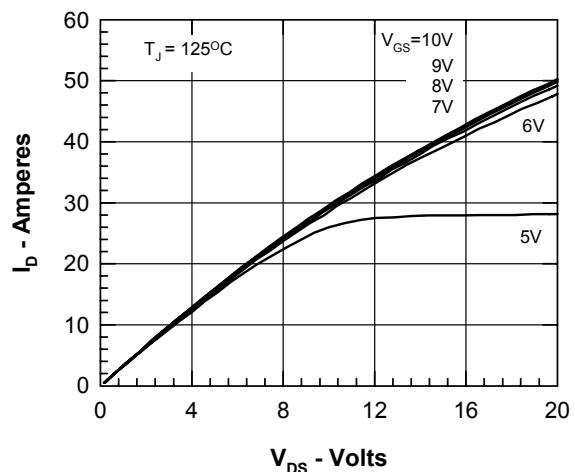


Figure 4.  $R_{DS(on)}$  normalized to 15A/25°C vs.  $T_J$

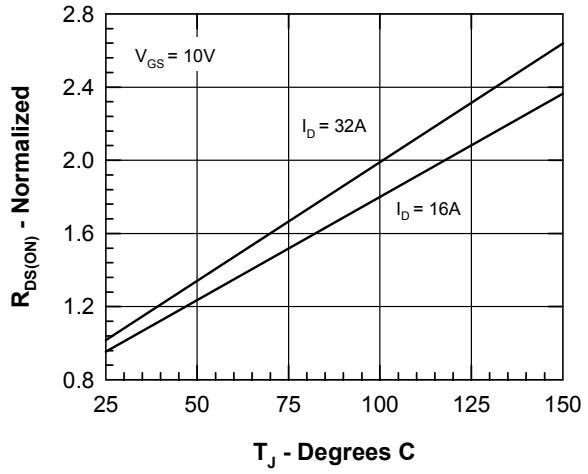


Figure 6. Admittance Curves

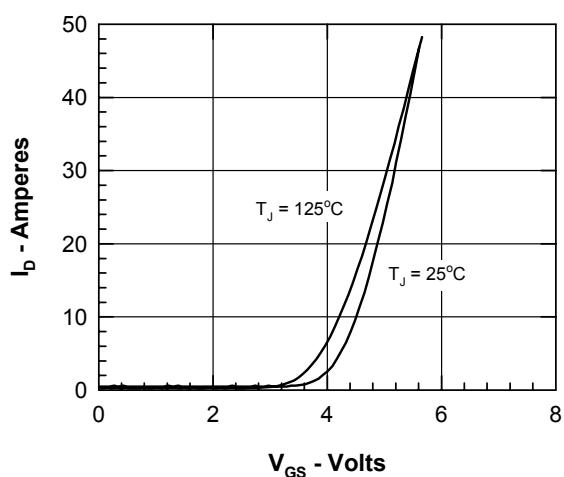


Figure 7. Gate Charge

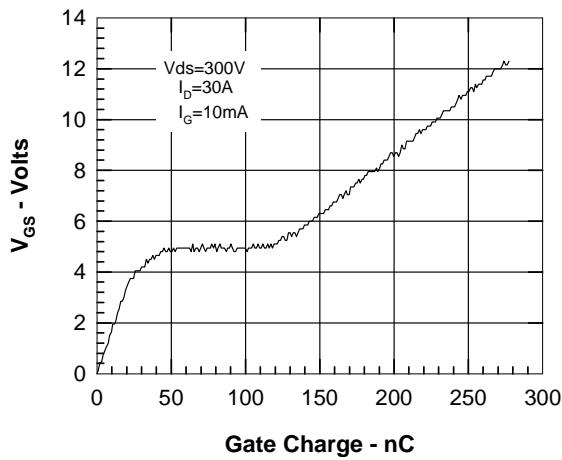


Figure 8. Capacitance Curves

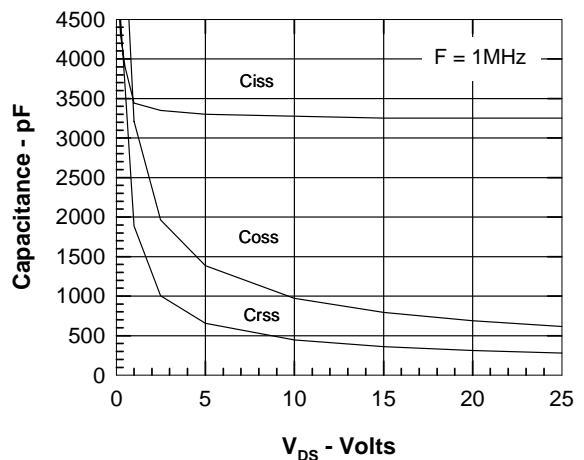


Figure 9. Forward Voltage Drop of the Intrinsic Diode

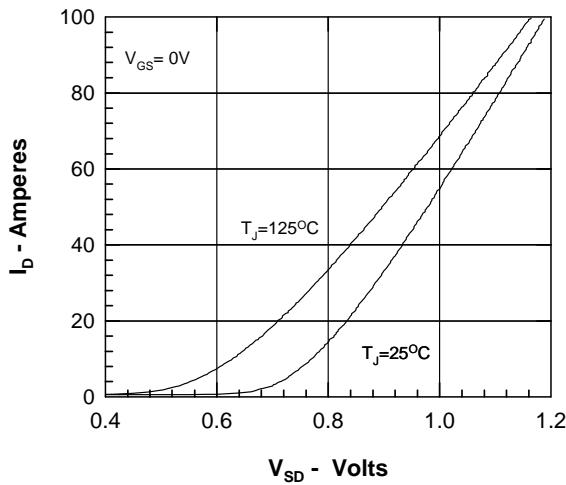


Figure 10. Transient Thermal Resistance

